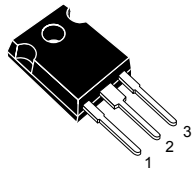
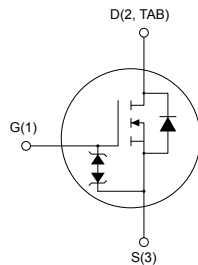


## N-channel 600 V, 35 mΩ typ., 63 A MDmesh™ M6 Power MOSFET in a TO-247 package


**TO-247**


AM01479V1



### Features

| Order code | V <sub>DS</sub> | R <sub>DS(on)</sub> max. | I <sub>D</sub> |
|------------|-----------------|--------------------------|----------------|
| STW68N60M6 | 600 V           | 41 mΩ                    | 63 A           |

- Reduced switching losses
- Lower R<sub>DS(on)</sub> per area vs previous generation
- Low gate input resistance
- 100% avalanche tested
- Zener-protected

### Applications

- Switching applications
- LLC converters
- Boost PFC converters

### Description

The new MDmesh™ M6 technology incorporates the most recent advancements to the well-known and consolidated MDmesh family of SJ MOSFETs. STMicroelectronics builds on the previous generation of MDmesh devices through its new M6 technology, which combines excellent R<sub>DS(on)</sub> per area improvement with one of the most effective switching behaviors available, as well as a user-friendly experience for maximum end-application efficiency.

#### Maturity status link

[STW68N60M6](#)

#### Device summary

|                   |            |
|-------------------|------------|
| <b>Order code</b> | STW68N60M6 |
| <b>Marking</b>    | 68N60M6    |
| <b>Package</b>    | TO-247     |
| <b>Packing</b>    | Tube       |

# 1 Electrical ratings

**Table 1. Absolute maximum ratings**

| Symbol         | Parameter   | Value      | Unit             |
|----------------|---|------------|------------------|
| $V_{GS}$       | Gate-source voltage   | $\pm 25$   | V                |
| $I_D$          | Drain current (continuous) at $T_C = 25\text{ }^\circ\text{C}$  | 63         | A                |
|                | Drain current (continuous) at $T_C = 100\text{ }^\circ\text{C}$ | 40         | A                |
| $I_{DM}^{(1)}$ | Drain current (pulsed)  | 252        | A                |
| $P_{TOT}$      | Total power dissipation at $T_C = 25\text{ }^\circ\text{C}$     | 390        | W                |
| $dv/dt^{(2)}$  | Peak diode recovery voltage slope                               | 15         | V/ns             |
| $dv/dt^{(3)}$  | MOSFET $dv/dt$ ruggedness                                       | 100        |                  |
| $T_{stg}$      | Storage temperature range                                       | -55 to 150 | $^\circ\text{C}$ |
| $T_j$          | Operating junction temperature range                            |            |                  |

1. Pulse width is limited by safe operating area.
2.  $I_{SD} \leq 63\text{ A}$ ,  $di/dt \leq 400\text{ A}/\mu\text{s}$ ,  $V_{DS(peak)} < V_{(BR)DSS}$ ,  $V_{DD} = 400\text{ V}$
3.  $V_{DS} \leq 480\text{ V}$

**Table 2. Thermal data**

| Symbol         | Parameter                           | Value | Unit                      |
|----------------|-------------------------------------|-------|---------------------------|
| $R_{thj-case}$ | Thermal resistance junction-case    | 0.32  | $^\circ\text{C}/\text{W}$ |
| $R_{thj-amb}$  | Thermal resistance junction-ambient | 50    | $^\circ\text{C}/\text{W}$ |

**Table 3. Avalanche characteristics**

| Symbol   | Parameter  | Value | Unit |
|----------|--|-------|------|
| $I_{AR}$ | Avalanche current, repetitive or not repetitive (pulse width limited by $T_{jmax}$ )                                 | 7.5   | A    |
| $E_{AS}$ | Single pulse avalanche energy (starting $T_j = 25\text{ }^\circ\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50\text{ V}$ ) | 1100  | mJ   |

## 2 Electrical characteristics

( $T_C = 25\text{ °C}$  unless otherwise specified)

**Table 4. On /off-states**

| Symbol        | Parameter                         | Test conditions   | Min. | Typ. | Max.    | Unit          |
|---------------|-----------------------------------|---|------|------|---------|---------------|
| $V_{(BR)DSS}$ | Drain-source breakdown voltage    | $V_{GS} = 0\text{ V}, I_D = 1\text{ mA}$                                | 600  |      |         | V             |
| $I_{DSS}$     | Zero-gate voltage drain current   | $V_{GS} = 0\text{ V}, V_{DS} = 600\text{ V}$                            |      |      | 1       | $\mu\text{A}$ |
|               |                                   | $V_{GS} = 0\text{ V}, V_{DS} = 600\text{ V}, T_C = 125\text{ °C}^{(1)}$ |      |      | 100     |               |
| $I_{GSS}$     | Gate-body leakage current         | $V_{DS} = 0\text{ V}, V_{GS} = \pm 25\text{ V}$                         |      |      | $\pm 5$ | $\mu\text{A}$ |
| $V_{GS(th)}$  | Gate threshold voltage            | $V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$                         | 3.25 | 4    | 4.75    | V             |
| $R_{DS(on)}$  | Static drain-source on-resistance | $V_{GS} = 10\text{ V}, I_D = 31.5\text{ A}$                             |      | 35   | 41      | m $\Omega$    |

1. Defined by design, not subject to production test.

**Table 5. Dynamic**

| Symbol                     | Parameter                     | Test conditions   | Min. | Typ. | Max. | Unit     |
|----------------------------|-------------------------------|---|------|------|------|----------|
| $C_{iss}$                  | Input capacitance             | $V_{GS} = 0\text{ V}, V_{DS} = 100\text{ V}, f = 1\text{ MHz}$  | -    | 4360 | -    | pF       |
| $C_{oss}$                  | Output capacitance            |   | -    | 235  | -    | pF       |
| $C_{rss}$                  | Reverse transfer capacitance  |   | -    | 13   | -    | pF       |
| $C_{oss\text{ eq.}}^{(1)}$ | Equivalent output capacitance | $V_{GS} = 0\text{ V}, V_{DS} = 0\text{ to }480\text{ V}$  | -    | 713  | -    | pF       |
| $R_G$                      | Intrinsic gate resistance     | $f = 1\text{ MHz}$ open drain   | -    | 1.6  | -    | $\Omega$ |
| $Q_g$                      | Total gate charge             | $V_{DD} = 480\text{ V}, I_D = 63\text{ A},$<br>$V_{GS} = 0\text{ to }10\text{ V}$<br>(see Figure 14. Test circuit for gate charge behavior) | -    | 106  | -    | nC       |
| $Q_{gs}$                   | Gate-source charge            |   | -    | 29   | -    | nC       |
| $Q_{gd}$                   | Gate-drain charge             |   | -    | 51   | -    | nC       |

1.  $C_{oss\text{ eq.}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ .

**Table 6. Switching times**

| Symbol       | Parameter           | Test conditions   | Min. | Typ. | Max. | Unit |
|--------------|---------------------|---|------|------|------|------|
| $t_{d(on)}$  | Turn-on delay time  | $V_{DD} = 300\text{ V}, I_D = 30\text{ A},$<br>$R_G = 4.7\text{ }\Omega, V_{GS} = 10\text{ V}$<br>(see Figure 13. Test circuit for resistive load switching times and Figure 18. Switching time waveform) | -    | 42   | -    | ns   |
| $t_r$        | Rise time           |   | -    | 28   | -    | ns   |
| $t_{d(off)}$ | Turn-off delay time |   | -    | 130  | -    | ns   |
| $t_f$        | Fall time           |   | -    | 8    | -    | ns   |

**Table 7. Source-drain diode**

| Symbol          | Parameter                     | Test conditions   | Min. | Typ. | Max. | Unit          |
|-----------------|-------------------------------|---|------|------|------|---------------|
| $I_{SD}$        | Source-drain current          |   | -    |      | 63   | A             |
| $I_{SDM}^{(1)}$ | Source-drain current (pulsed) |   | -    |      | 252  | A             |
| $V_{SD}^{(2)}$  | Forward on voltage            | $V_{GS} = 0\text{ V}$ , $I_{SD} = 63\text{ A}$  | -    |      | 1.6  | V             |
| $t_{rr}$        | Reverse recovery time         | $I_{SD} = 63\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$ ,   | -    | 308  |      | ns            |
| $Q_{rr}$        | Reverse recovery charge       | $V_{DD} = 60\text{ V}$ (see<br>Figure 15. Test circuit for<br>inductive load switching and<br>diode recovery times)                                     | -    | 4.3  |      | $\mu\text{C}$ |
| $I_{RRM}$       | Reverse recovery current      |   | -    | 26   |      | A             |
| $t_{rr}$        | Reverse recovery time         | $I_{SD} = 63\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$ ,   | -    | 504  |      | ns            |
| $Q_{rr}$        | Reverse recovery charge       | $V_{DD} = 60\text{ V}$ , $T_j = 150\text{ }^\circ\text{C}$<br>(see Figure 15. Test circuit for<br>inductive load switching and<br>diode recovery times) | -    | 10.8 |      | $\mu\text{C}$ |
| $I_{RRM}$       | Reverse recovery current      |   | -    | 38   |      | A             |

1. Pulse width is limited by safe operating area.
2. Pulse test: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%.

## 2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

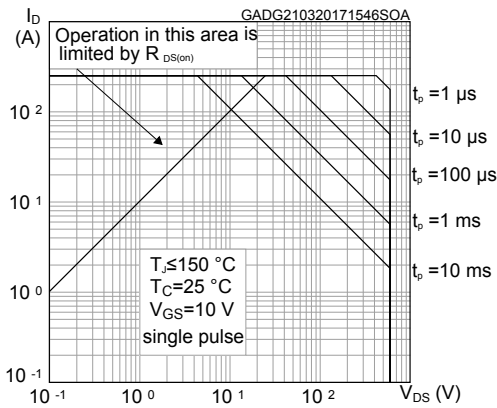


Figure 2. Thermal impedance

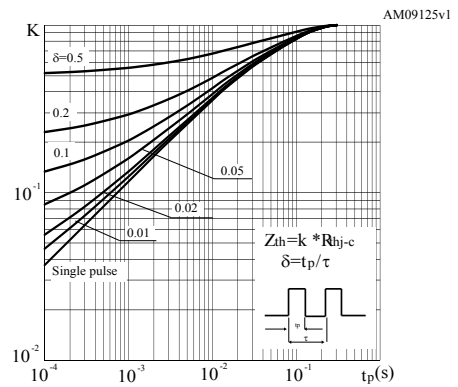


Figure 3. Output characteristics

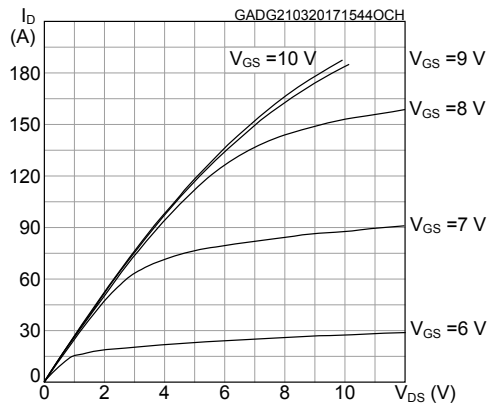


Figure 4. Transfer characteristics

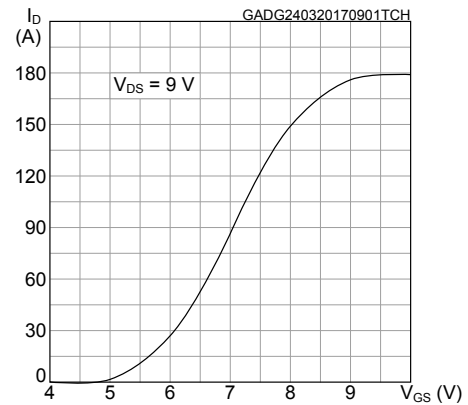


Figure 5. Gate charge vs gate-source voltage

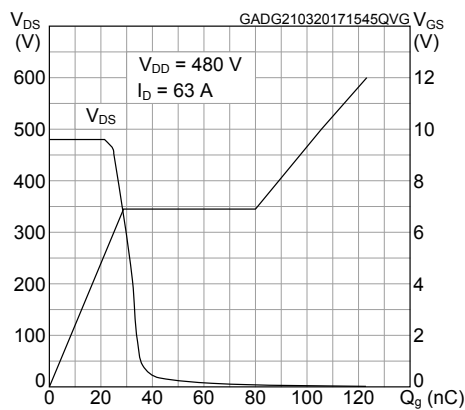


Figure 6. Static drain-source on-resistance

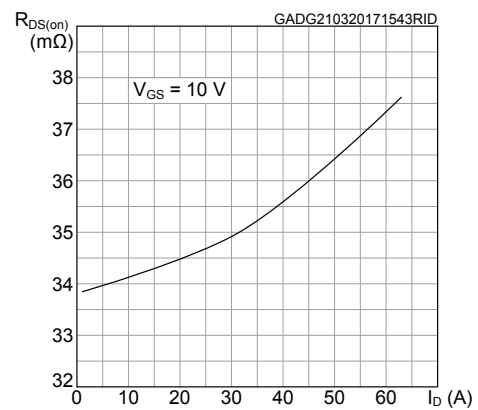


Figure 7. Capacitance variations

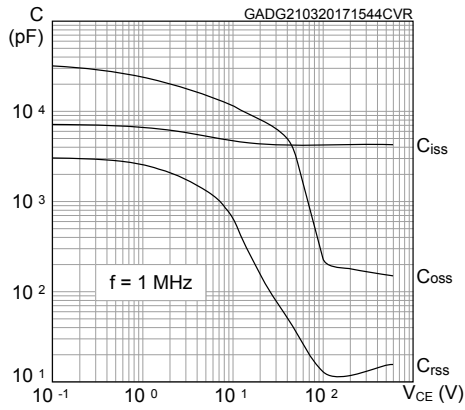


Figure 8. Normalized gate threshold vs. temperature

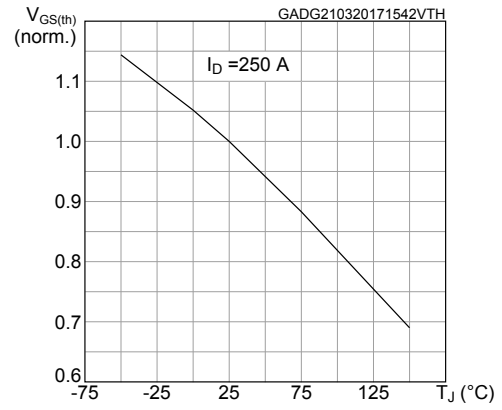


Figure 9. Normalized on-resistance vs. temperature

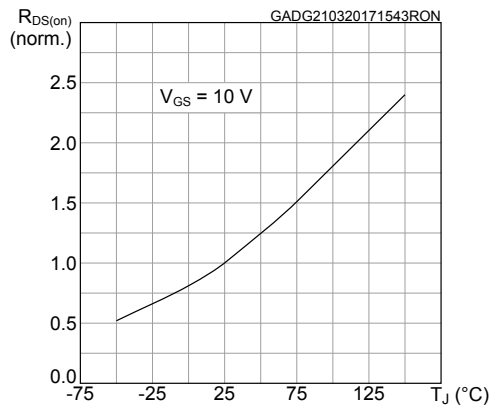


Figure 10. Normalized V(BR)DSS vs. temperature

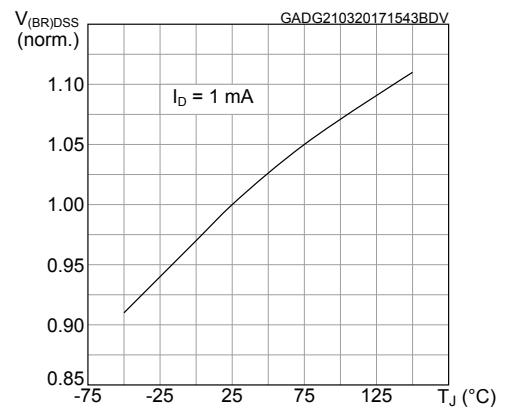


Figure 11. Output capacitance stored energy

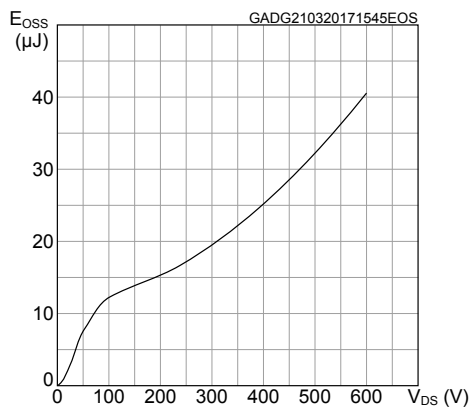
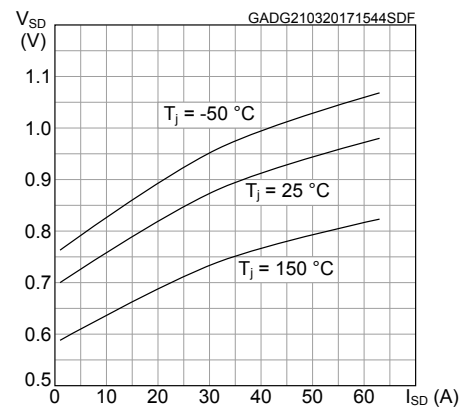
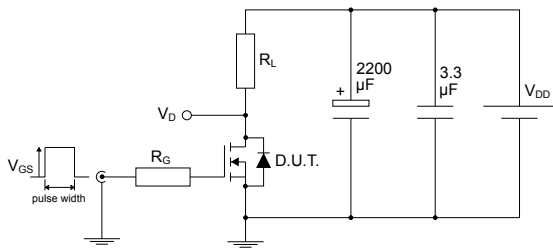


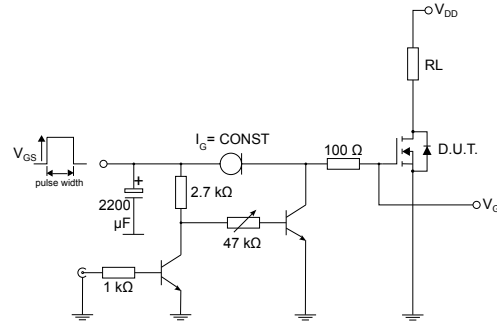
Figure 12. Source-drain diode forward characteristics



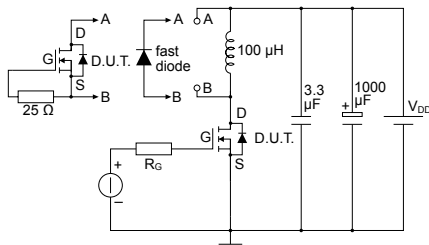
### 3 Test circuits

**Figure 13. Test circuit for resistive load switching times**


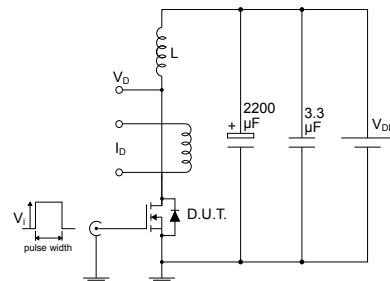
AM01468v1

**Figure 14. Test circuit for gate charge behavior**


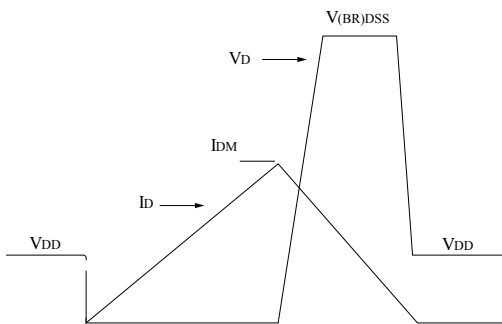
AM01469v10

**Figure 15. Test circuit for inductive load switching and diode recovery times**


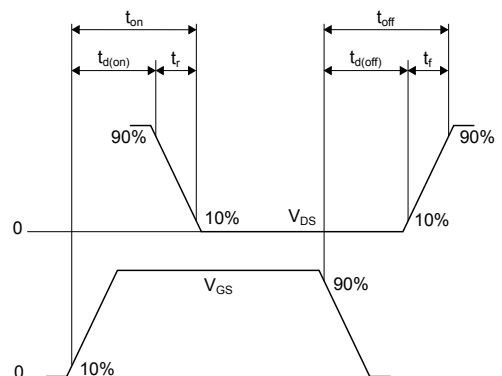
AM01470v1

**Figure 16. Unclamped inductive load test circuit**


AM01471v1

**Figure 17. Unclamped inductive waveform**


AM01472v1

**Figure 18. Switching time waveform**


AM01473v1

## 4 Package information

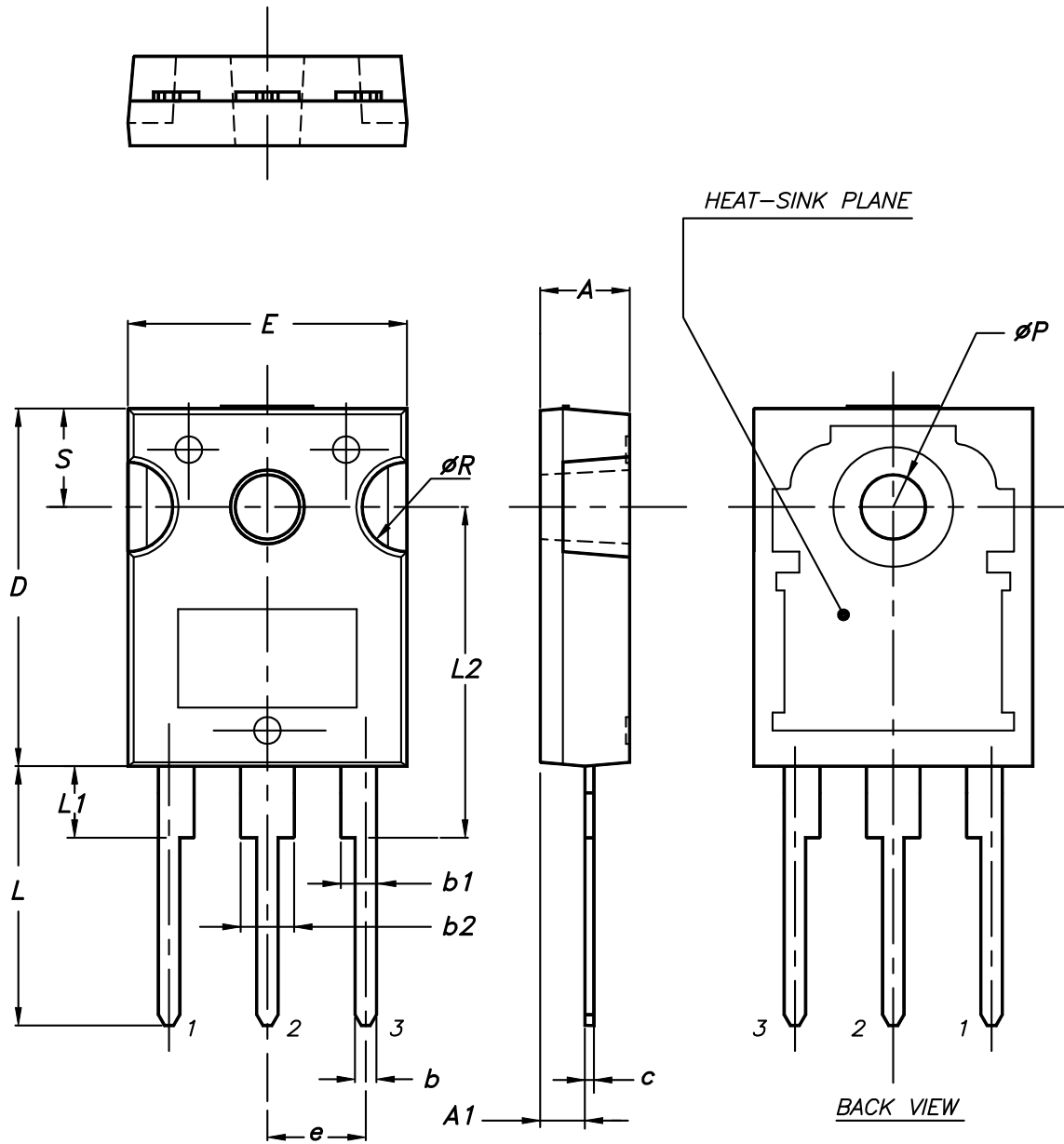
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In order to meet environmental requirements, ST offers these devices in different grades of **ECOPACK®** packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com). ECOPACK® is an ST trademark.



## 4.1 TO-247 package information

Figure 19. TO-247 package outline



0075325\_9

**Table 8. TO-247 package mechanical data**

| Dim. | mm    |       |       |
|------|-------|-------|-------|
|      | Min.  | Typ.  | Max.  |
| A    | 4.85  |       | 5.15  |
| A1   | 2.20  |       | 2.60  |
| b    | 1.0   |       | 1.40  |
| b1   | 2.0   |       | 2.40  |
| b2   | 3.0   |       | 3.40  |
| c    | 0.40  |       | 0.80  |
| D    | 19.85 |       | 20.15 |
| E    | 15.45 |       | 15.75 |
| e    | 5.30  | 5.45  | 5.60  |
| L    | 14.20 |       | 14.80 |
| L1   | 3.70  |       | 4.30  |
| L2   |       | 18.50 |       |
| ØP   | 3.55  |       | 3.65  |
| ØR   | 4.50  |       | 5.50  |
| S    | 5.30  | 5.50  | 5.70  |

## Revision history

**Table 9. Document revision history**

| Date        | Revision | Changes  |
|-------------|----------|--|
| 27-Mar-2017 | 1        | First release.   |
| 05-Nov-2018 | 2        | <p>Removed maturity status indication from cover page. The document status is production data.</p> <p>Modified <a href="#">Table 1. Absolute maximum ratings</a>, <a href="#">Table 5. Dynamic</a> and <a href="#">Table 7. Source-drain diode</a></p> <p>Modified <a href="#">Figure 1. Safe operating area</a>, <a href="#">Figure 3. Output characteristics</a>, <a href="#">Figure 4. Transfer characteristics</a>, <a href="#">Figure 5. Gate charge vs gate-source voltage</a>, <a href="#">Figure 6. Static drain-source on-resistance</a>, <a href="#">Figure 7. Capacitance variations</a>, <a href="#">Figure 8. Normalized gate threshold vs. temperature</a>, <a href="#">Figure 9. Normalized on-resistance vs. temperature</a>, <a href="#">Figure 10. Normalized <math>V_{(BR)DSS}</math> vs. temperature</a> and <a href="#">Figure 12. Source-drain diode forward characteristics</a>.</p> <p>Minor text changes.</p> |

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